

Search Notes

Application/Control No.

10/695,245

Examiner

Jermele M. Hollington

Applicant(s)/Patent under
Reexamination

ORSILLO, JAMES F.

Art Unit

2829

SEARCHED

Class	Subclass	Date	Examiner
324	754-755 758 761	6/7/2005	JMH
↓	765 158.1	↓	↓
439	482		
29	832		
414	591-592		
209	573-574	↓	↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Talk with Vinh Nguyen about a search on testing semiconductor devices using probe station; WEST search	6/7/2005	JMH